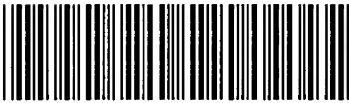


Search Notes

Application/Control No.

10/760,522

Examiner

Dwin M. Craig

Applicant(s)/Patent under
Reexamination

NAKAMURA ET AL.

Art Unit

2123

SEARCHED

Class	Subclass	Date	Examiner
703	6	11/22/2006	/DC/
716	19,21	11/22/2006	/DC/

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PALM (Inventor name search)	11/22/2006	/DC/
EAST(US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) see search notes for search terms	11/22/2006	/DC/
ACM (see search notes for search terms)	11/22/2006	/DC/
GOOGLE Scholar (Inventor name search)	11/22/2006	/DC/
IEEE (see search notes for the search terms)	11/22/2006	/DC/
EAST(US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) see search notes for search terms	12/28/2006	/DC/
EAST(US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) see search notes for search terms	12/8/2006	/DC/
EAST(US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) see search note	12/9/2006	/DC/